IN THE CLAIMS:

Please amend claims 4, 5, 8, 9, 10, 11, 13, 14, 15, 16, and 19, as follows:

1. (Original) A method of producing a porous insulating film, comprising the step of:

introducing gas containing vapor of cyclic organic silica compounds, which have silicon and oxygen skeletons and have at least one unsaturated hydrocarbon group bound with a side chain of a skeleton, into plasma to grow a porous insulating film on a semiconductor substrate.

2. (Original) A method of producing a porous insulating film, comprising the step of:

introducing vapor of cyclic organic silica compounds, which have silicon and oxygen skeletons and have at least one unsaturated hydrocarbon group bound with a side chain of a skeleton, and vapor of straight-chain organic silica compounds, which have silicon and oxygen skeletons and have any one selected from the group consisting of hydrogen, a hydrocarbon group and a hydrocarbon oxide group bound with a side chain of a skeleton, into plasma to grow a porous insulating film on a semiconductor substrate.

3. (Original) The method of producing a porous insulating film according to claim 2, wherein said straight-chain organic silica compounds have a structure represented by the following formula (1):

where R_1 to R_6 , which may be the same or different, respectively represent any one selected from the group consisting of hydrogen, a hydrocarbon group and a hydrocarbon oxide group; or

where R_1 to R_4 , which may be the same or different, respectively represent any one selected from the group consisting of hydrogen, a hydrocarbon group and a hydrocarbon oxide group; or

where R_1 to R_4 , which may be the same or different, respectively represent any one selected from the group consisting of hydrogen, a hydrocarbon group and a hydrocarbon oxide group; or

where R_1 to R_4 , which may be the same or different, respectively represent any one selected from the group consisting of hydrogen, a hydrocarbon group and a hydrocarbon oxide group.

- 4. (Currently Amended) The method of producing a porous insulating film according to claim 2 or 3, wherein a supply ratio of said cyclic organic silica compounds to said straight-chain organic silica compounds is changed during film formation.
- 5. (Currently Amended) The method of producing a porous insulating film according to any one of claims 1, 2 and 4 claim 1, wherein said cyclic organic silica compounds are cyclosiloxane monomers represented by the following formula (2):

 $\begin{bmatrix}
R_1 \\
I \\
s_{i0}
\end{bmatrix}$

[formula 2]

(2) Cyclosiloxane monomer

where R_1 and R_2 are respectively any one of the group consisting of hydrogen, an alkyl group, an alkoxide group, an amino group, alkene, alkyne, a phenyl group and a phenol group, provided that R_1 and R_2 may be the same or different, provided that at least one of the side chain groups is an unsaturated hydrocarbon group, and n is an integer of 2 or more.

6. (Original) The method of producing a porous insulating film according to claim 5, wherein said cyclic organic silica compounds are trivinylcyclotrisiloxane derivative monomers represented by the following formula (3):

[formula 3]

- (3) Trivinylcyclotrisiloxane derivative
- 7. (Original) The method of producing a porous insulating film according to claim 5, wherein said cyclic organic silica compound is tetravinyltetramethylcyclotetrasiloxane monomers represented by the following formula (4):

[formula 4]

(4) Tetravinyltetramethylcyclotetrasiloxane

8. (Currently Amended) The method of producing a porous insulating film according to any one of claims 2 and 4 claim 2, wherein said cyclic organic silica compounds are tetravinyltetramethyl-cyclotetrasiloxane monomers represented by the formula (4) and said straight-chain organic silica compounds are divinylsiloxanebenzocyclobutene monomers represented by the following formula (5):

[formula 5]

- (5) Divinylsiloxanebenzocyclobutene
- 9. (Currently Amended) The method of producing a porous insulating film according to any one of claims 1 to 8 claim 1, wherein said plasma is plasma of rare gas.
- 10. (Currently Amended) A semiconductor device according to any one of claims 1 to 9 claim 1, wherein said plasma is plasma of mixture gas of rare gas and oxidizer gas or hydrogenated silicon gas.

- 11. (Currently Amended) A porous insulating film produced by the method of producing a porous insulating film according to any one of claims 1 to 10 claim 1.
- 12. (Original) The porous insulating film according to claim 11, comprising at least silicon, carbon, oxygen and hydrogen and having a Raman spectrum corresponding to at least three-membered silica skeleton in the Raman spectroscopic analysis.
- 13. (Currently Amended) The porous insulating film according to claims 11 or 12 claim 11, wherein ratios of elements in the film is: O/Si = 0.8 to 1.2, C/Si = 1.5 to 10.0 and H/Si = 4.0 to 15.0.
- 14. (Currently Amended) The porous insulating film according to claim 11, 12 or 13, wherein the diameter of pores contained in the film is 3 nm or less.
- 15. (Currently Amended) The porous insulating film according to any one of claims 11 to 14 claim 11, wherein at least a part of pores contained in the film have almost the same diameters as a skeleton of said cyclic organic silica compounds.
- 16. (Currently Amended) A semiconductor device using the porous insulating film according to any one of claims 11 to 15 claim 11 as a layer insulating film of a multilayer wiring.
- 17. (Original) The semiconductor device according to claim 16, wherein in the vicinity of a interface between the porous insulating film and a non-porous insulating film, a relative concentration of carbon atom in at least the porous insulating film changes stepwise or continuously.

- 18. (Original) The semiconductor device according to claim 17, wherein said straight-chain organic silica compounds have a structure represented by said formula (1).
- 19. (Currently Amended) The semiconductor device according to claim 16-or 17, wherein said cyclic organic silica compounds are cyclosiloxane monomers represented by said formula (2), where R₁ and R₂ are any one selected from the group consisting of hydrogen, an alkyl group, an alkoxide group, an amino group, alkene, alkyne, a phenyl group and a phenol group, provided that R₁ and R₂may be the same or different, provided that at least one of side chain groups is an unsaturated hydrocarbon group, and n is an integer of 2 or more.
- 20. (Original) The semiconductor device according to claim 19, wherein said cyclic organic silica compounds are tetravinyltetramethylcyclotetrasiloxane monomers represented by said formula (4).
- 21. (Original) The semiconductor device according to claim 19, wherein said cyclic organic silica compounds are trivinylcyclotrisiloxane derivative monomers represented by said formula (3).
- 22. (Original) The semiconductor device according to claim 18, wherein said straight-chain organic silica compounds are divinylsiloxanebenzocyclobutene monomers represented by said formula (5).